

**Search Notes**

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

CHANG, WON-KIL

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	1,22,29 30,32,33 81	5/19/2005	SWH
15	250.361	5/19/2005	SWH
101	155	5/19/2005	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
347	33	5/19/2005	SWH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR